

PATENT
450100-04677**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: **Takuji HIMENO et al.**

International Application No.: **PCT/JP03/08432**

International Filing Date: **July 2, 2003**

For: **IMAGE DATA PROCESSING APPARATUS AND METHOD**

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Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/08432. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

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DT15R PCT/PCT 06 JAN 2005
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REMARKS

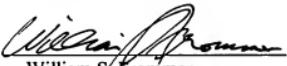
Entry of this Information Disclosure Statement and an early examination on the
merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
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Enclosures

0115 Resent to 06 JAN 2005

Sheet 1 of 1

Based on Form PTO-1449 (3/90)		ATTY. DOCKET NO. 450100-04677	SERIAL NO. 10/520,445 Filed Concurrently Herewith
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Takuji HIMENO et al.	
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U.S. PATENT DOCUMENTS

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/D.H./	AL	JP 10-308942	11/17/98	Japan	_____	_____	
D.H./	AM	JP 2000-92448	03/31/00	Japan	_____	_____	
/D.H./	AN	JP 2001-275077	10/05/01	Japan	_____	_____	
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